## **Growth Morphology and Defects in 2D Heterostructures and Interfaces**

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Since the successful isolation of graphene, two-dimensional materials have rapidly moved to the forefront of "next generation" materials. The many applications range from enhancing the structural properties of composite material properties,<sup>1</sup> to water filtration,<sup>2</sup> biosensing,<sup>3</sup> catalysis,<sup>4</sup> photonics,<sup>5</sup> and ultra-low power electronics.<sup>6</sup> However, none of these applications will be possible without a concerted effort to develop techniques to understand how the 2D layers are grown and their material performance.

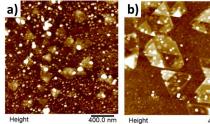
We have developed processes to synthesize a variety of 2D materials, with an emphasis on "beyond graphene" layers.<sup>7–9</sup> In the case of tungsten diselenide (WSe<sub>2</sub>), growth conditions, including temperature and total pressure, have a strong impact on the crystalline size, shape, and nucleation. Synthesis at high pressure results in a significant reduction in nucleation density and increase crystallite size, however, it also leads to the formation of particulates on the sample surface, which were subsequently identified as W-rich WSe<sub>2</sub> via cross-sectional transmission electron microscopy (TEM). The presence of such particles provided evidence that the selenium-to-tungsten (Se:W) ratio in vapor phase can be critical to achieving stoichiometric WSe<sub>2</sub>. As a result, the Se:W ratio is a critical factor in controlling defect formation in WSe<sub>2</sub>. This is evident in Figure 1a-d, which consists of atomic force microscopy scans of the WSe<sub>2</sub> surface, as a function of the Se:W ratio as it is increased from 170 to 14,000. The figure clearly demonstrates that domain size increases significantly as the Se:W ratio is increased, which is accompanied by a decrease in the density of W-rich WSe<sub>2</sub> particulates. Figure 1e is the cross-sectional HRTEM image of MOCVD grown multilayer WSe<sub>2</sub> directly on sapphire. HRTEM reveals some disorder at the WSe<sub>2</sub>/sapphire interface suggesting a reaction during growth, which is in agreement with previous works suggesting that sapphire (Al<sub>2</sub>O<sub>3</sub>) is not stable.

In addition to synthesis of WSe<sub>2</sub>, the synthesis of van der Waals heterostructures are also of increasing importance in the advancement of the field. Figure 2a shows the cross-sectional HRTEM image of CVD grown monolayer MoS<sub>2</sub> on bi-layer graphene and SiC substrate. The MoS<sub>2</sub> layer appears to be "blind" to thickness variations in the underlying graphene when there are no defects in the top layer of the graphene. However, when the top graphene layer is interrupted, the MoS<sub>2</sub> will also be discontinued, as indicated in the Figure 2a. Figure 2b shows HAADF image of monolayer MoS<sub>2</sub>/WSe<sub>2</sub> grown tri-layer graphene and SiC substrate. The contrast in a HAADF-STEM image is approximately proportional to  $Z^2$ , where Z is the atomic number. Using HAADF, the MoS<sub>2</sub> and WSe<sub>2</sub> layers were clearly distinguished, as shown in Figure 2c. There are existing monolayer WSe<sub>2</sub> with brightest contrast and monolayer MoS<sub>2</sub> with second brightest contrast. Finally, we note that defects and edge states in the base 2D layer lead to low energy nucleation sites, and therefore multilayer growth of a top layer is highly probable at these regions, as shown in in Figure 2c.

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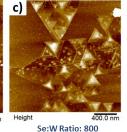
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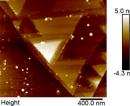
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Se:W Ratio: 170

Se:W Ratio: 400





Se:W Ratio: 14000

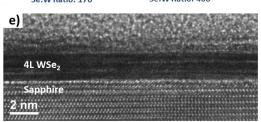


Figure 1: (a-d) AFM of a WSe2 surface as a function of increasing selenium (Se) overpressure that shows significant increase in domain size, as well as improved stoichiometry (reduction in particles). (e) TEM provides evidence that the sapphire substrate may be unstable during synthesis.

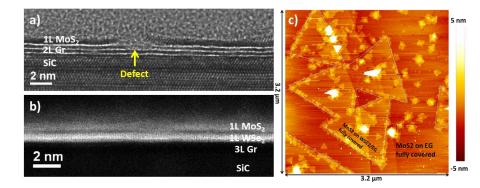


Figure 2: (a) TEM reveals that growth of 2D materials on graphene are highly sensitive to defects in the graphene. (b) TEM also provides evidence that multiple junction structures of MoS<sub>2</sub>/WSe<sub>2</sub> on graphene can be directly grown, where (c) defects and edges on WSe<sub>2</sub> leads to multilayer MoS<sub>2</sub>.